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SHEET 1 OF 1

Form PTO 1449	U.S. DEPARTMENT OF COMMERCE			ATTY DOCKET NO. 251011US6 SERIAL NO. 10/812,967					
(Modified)		PATENT AND TRAD	DEMARK OFFICE	251011US6 ATANDELIN			10/812,967		
				APPLICANT					
LIST OF	REFE	RENCES CITED BY AP	PLICANT	Toshihiro MORITA, et al.					
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				March 31, 2004			2615		
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